

# **Lecture 4**

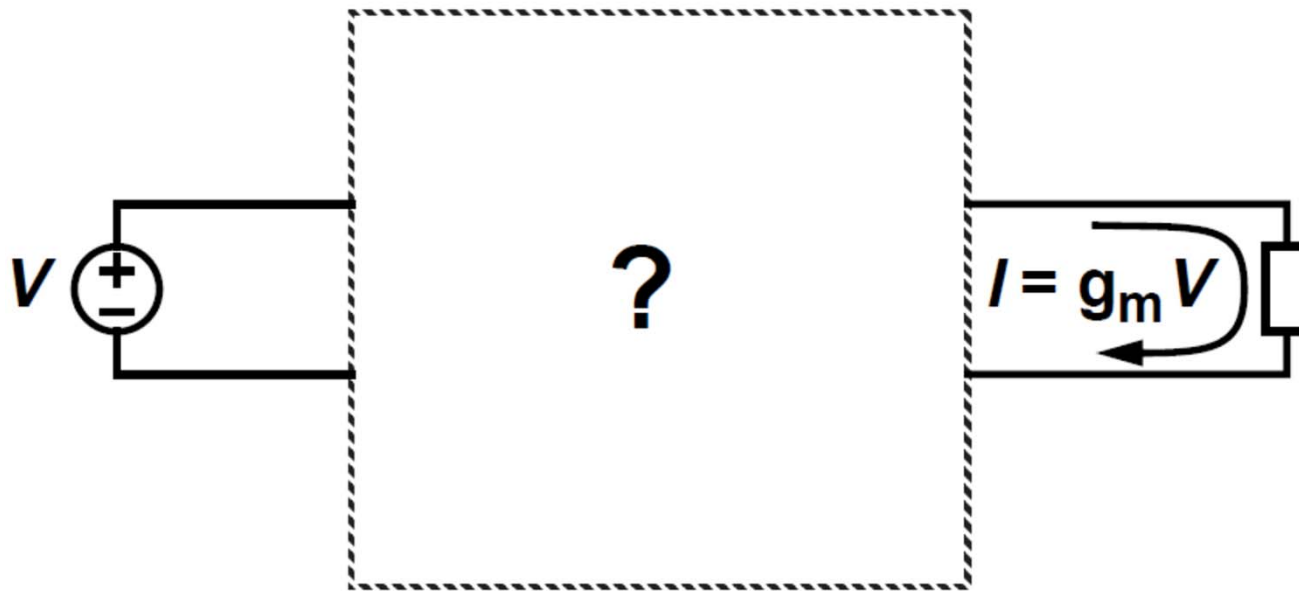
## **Comparator & Flash ADC Design**

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# Lecture Plan

Date	Lecture (Wednesday 2-4pm)		Reference	Homework
2020-01-07	1	MOD1 & MOD2	PST 2, 3, A	1: Matlab MOD1&2
2020-01-14	2	MODN + $\Delta\Sigma$ Toolbox	PST 4, B	2: $\Delta\Sigma$ Toolbox
2020-01-21	3	SC Circuits	R 12, CCJM 14	
2020-01-28	4	Comparator & Flash ADC	CCJM 10	3: Comparator
2020-02-04	5	Example Design 1	PST 7, CCJM 14	
2020-02-11	6	Example Design 2	CCJM 18	4: SC MOD2
2020-02-18	Reading Week / ISSCC			
2020-02-25	7	Amplifier Design 1		Project
2020-03-03	8	Amplifier Design 2		
2020-03-10	9	Noise in SC Circuits		
2020-03-17	10	Nyquist-Rate ADCs	CCJM 15, 17	
2020-03-24	11	Mismatch & MM-Shaping	PST 6	
2020-03-31	12	Continuous-Time $\Delta\Sigma$	PST 8	
2020-04-07	Exam			
2020-04-21	Project Presentation (Project Report Due at start of class)			

# Circuit of the Day: Linear Transconductor



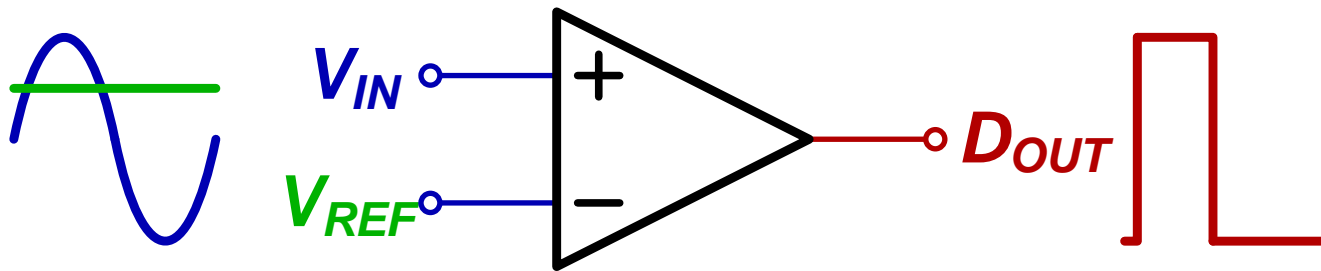
- Useful in many circuits
  1. Gm-C filter
  2. LNA
  3. Mixer
  4. Continuous-Time  $\Delta\Sigma$  ADC

# What you will learn...

- **Example Comparator Circuit**
- **Regeneration Time Constant  $\tau$**
- **Metastability, Probability of Error**
- **Offset, Auto-zeroing**
- **Flash ADC**

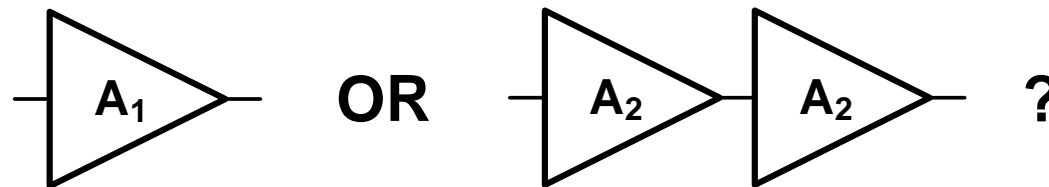
# Comparator

- **Basic building block of an A/D converter**  
Acts as a 1-bit A/D converter
- **Output amplifies difference between  $V_{IN}$  &  $V_{REF}$**   
With a large gain, output is 'digital' at either the positive or negative supply rail



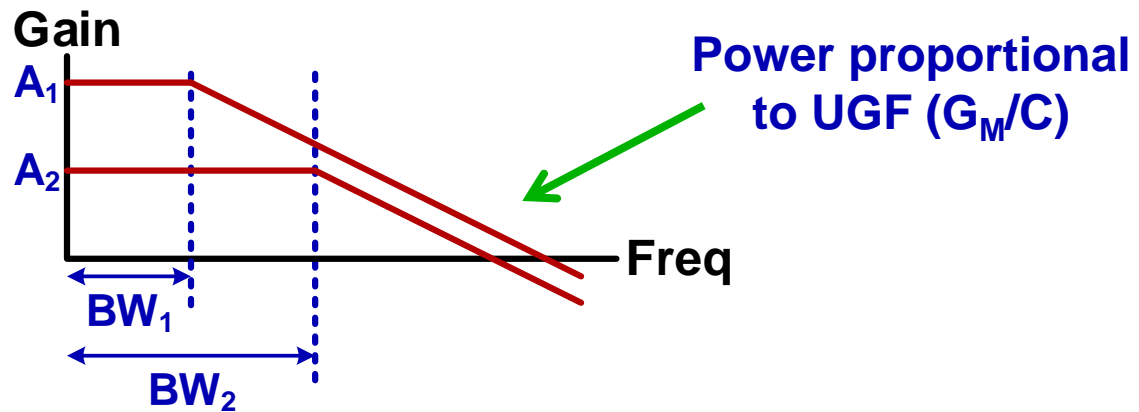
# Comparator

- Not an open-loop amplifier



Amplifier ( $A_1$ ) typically high gain, low 3dB frequency

Cascaded low-gain stages ( $A_2$ ) faster for a given power

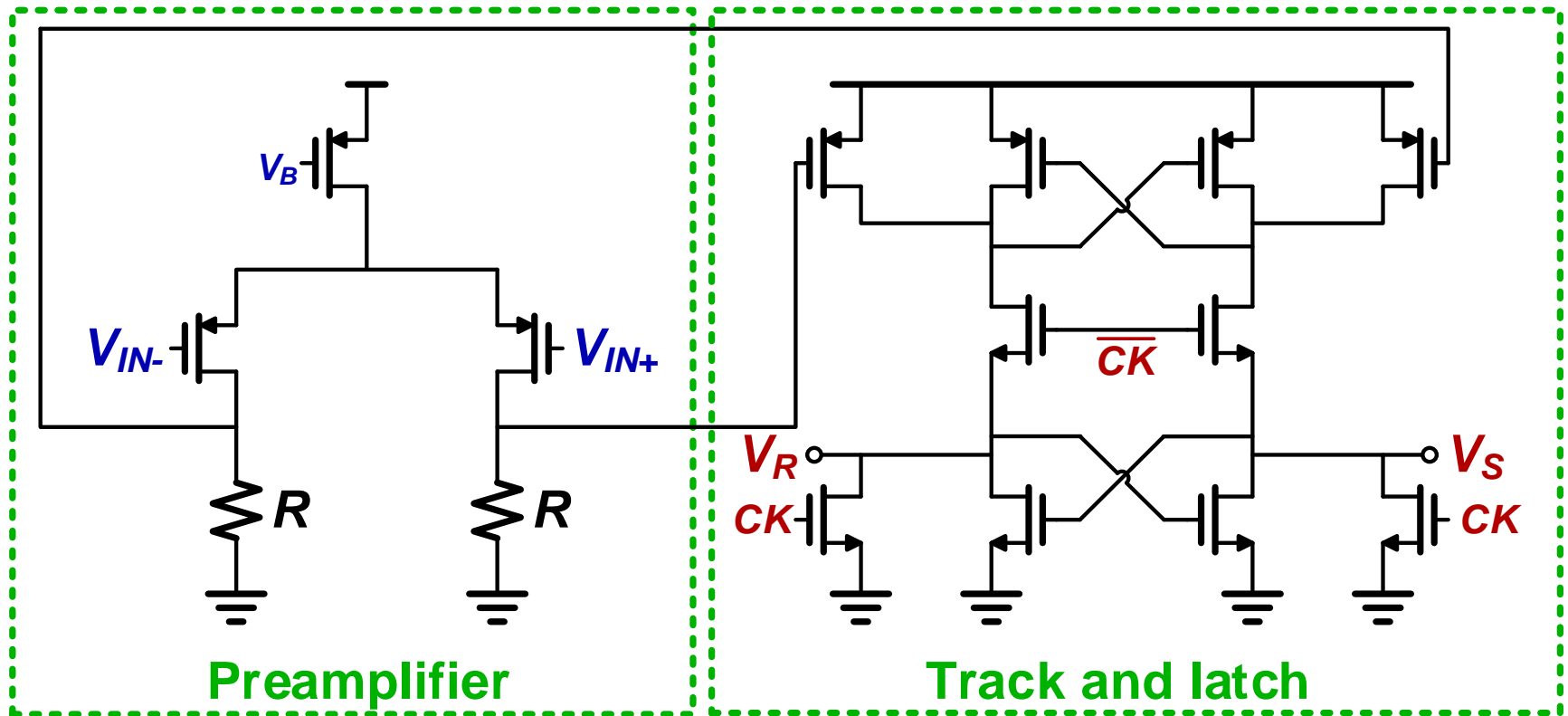


# Comparator

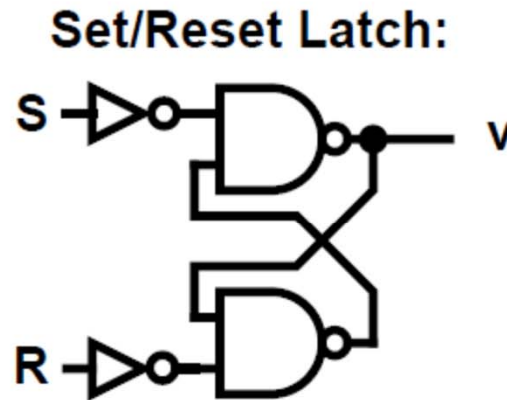
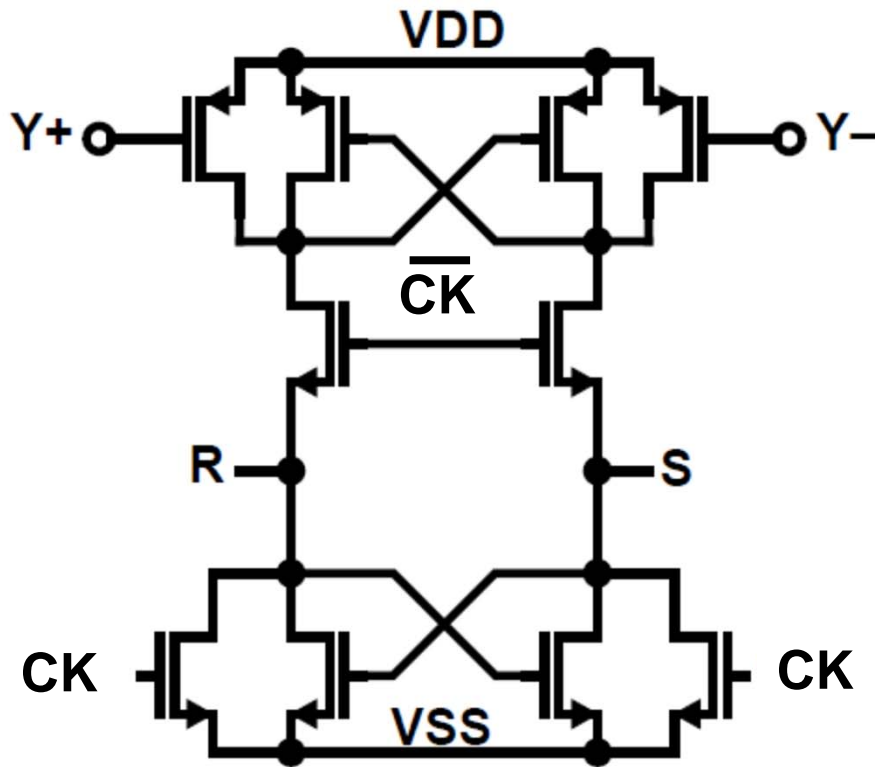
- Latched comparator

Track when CK high, precharge output low

Latch when CK low



# Comparator: Track and Latch



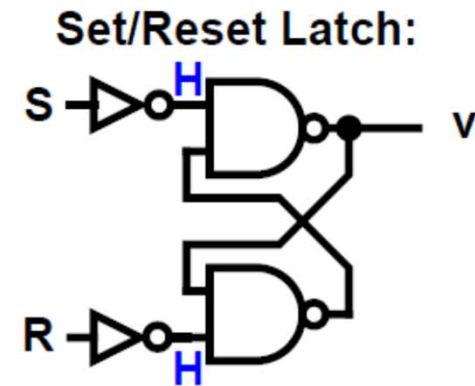
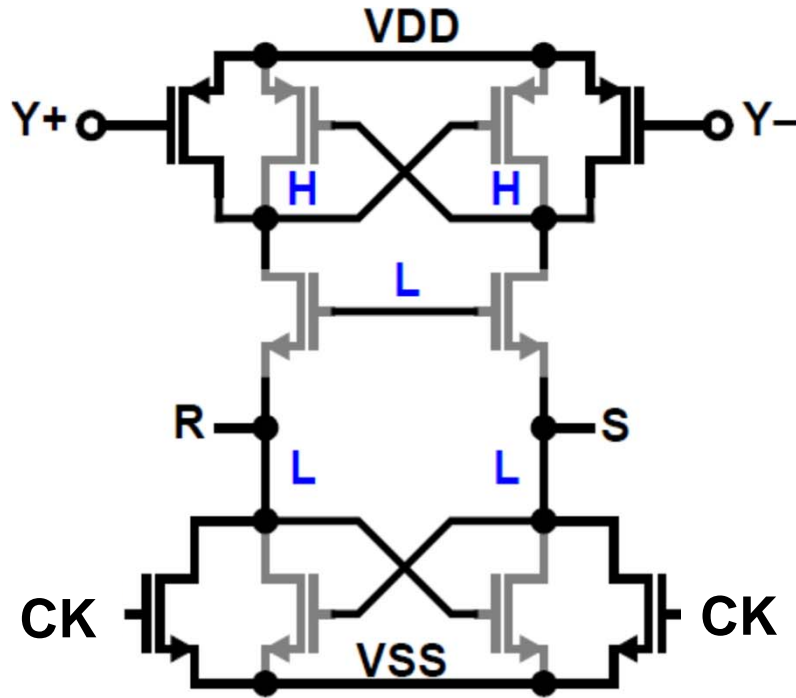
Inverter thresholds are chosen so that the inverters respond only after R/S have resolved.

- **Falling CK phase initiates regenerative action**  
S and R connected to a Set/Reset latch



# Comparator: Track and Latch

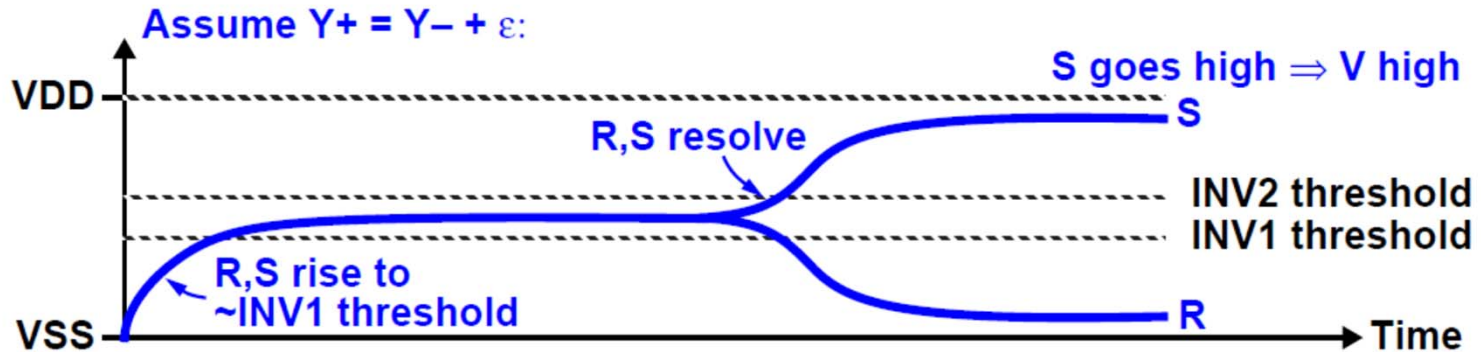
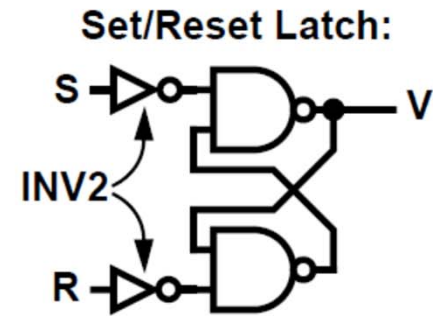
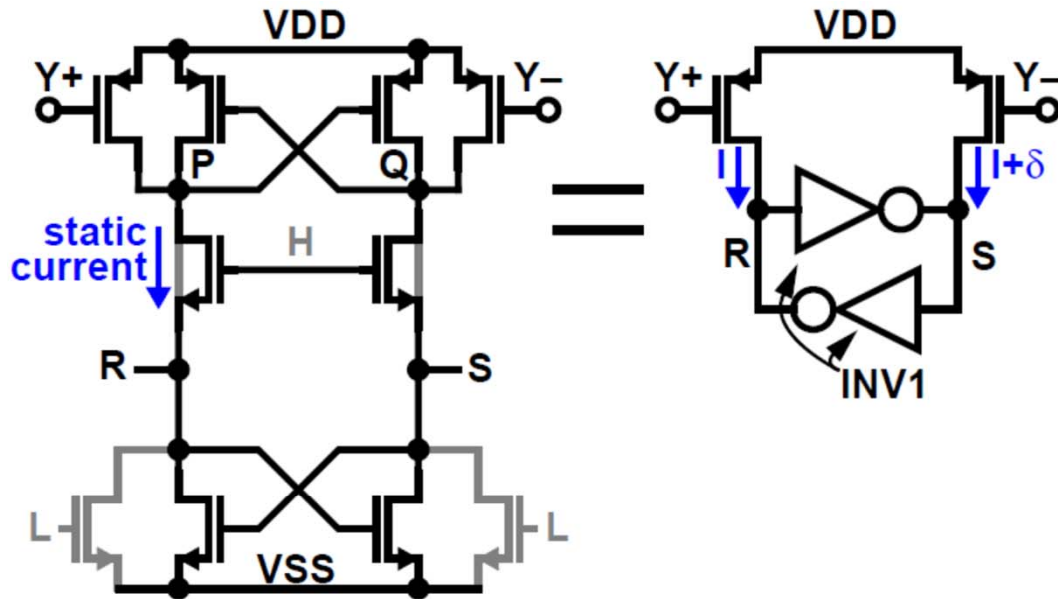
- CK is High: 'Reset' or 'Track' Mode



- Active part of the comparator is reset  
Grayed-out devices are off
- R and S are low  $\rightarrow$  the SR latch is in hold mode

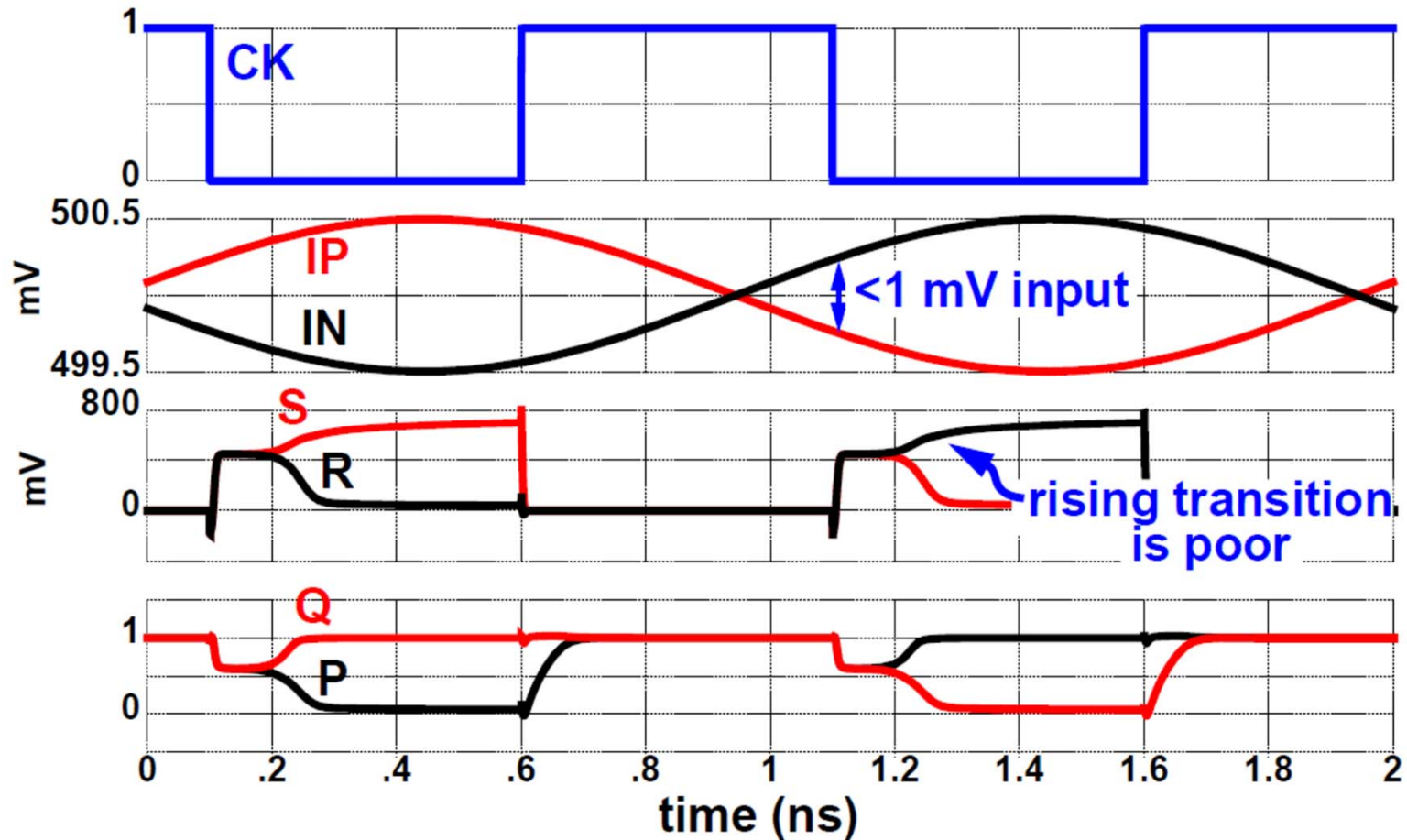
# Comparator: Track and Latch

- CK goes Low: 'Latch' Mode

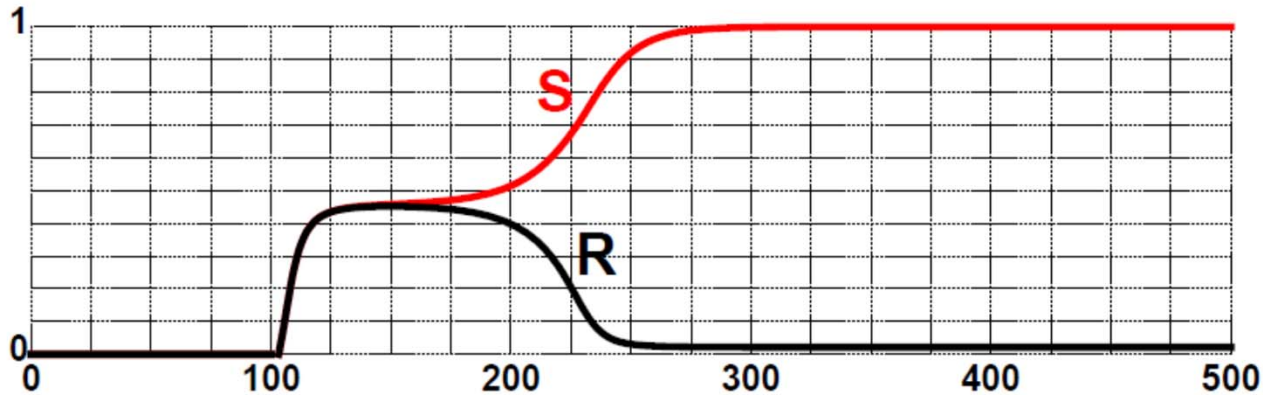
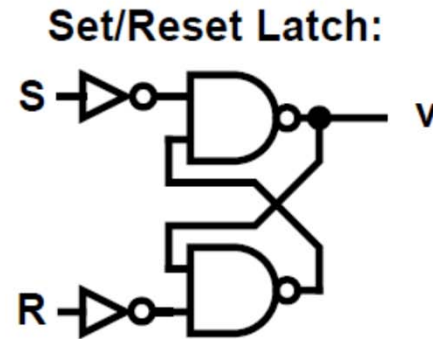
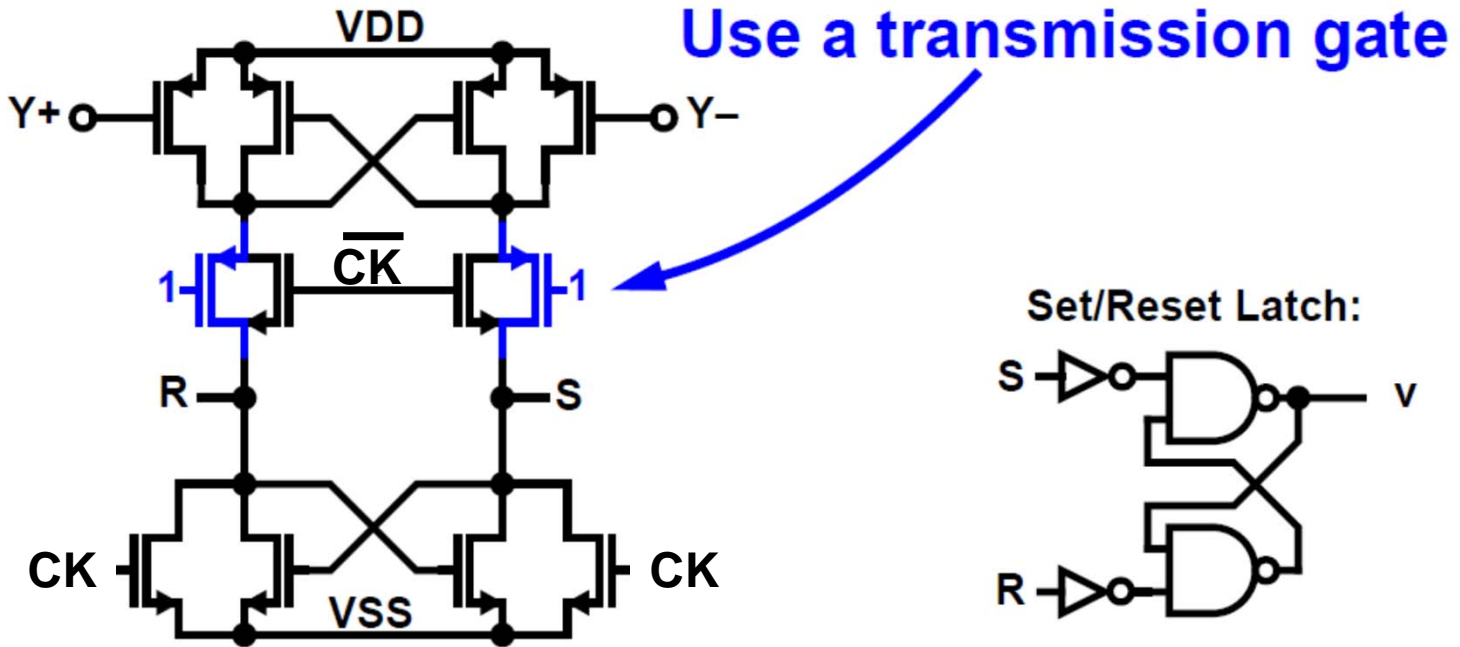


# Example Waveforms

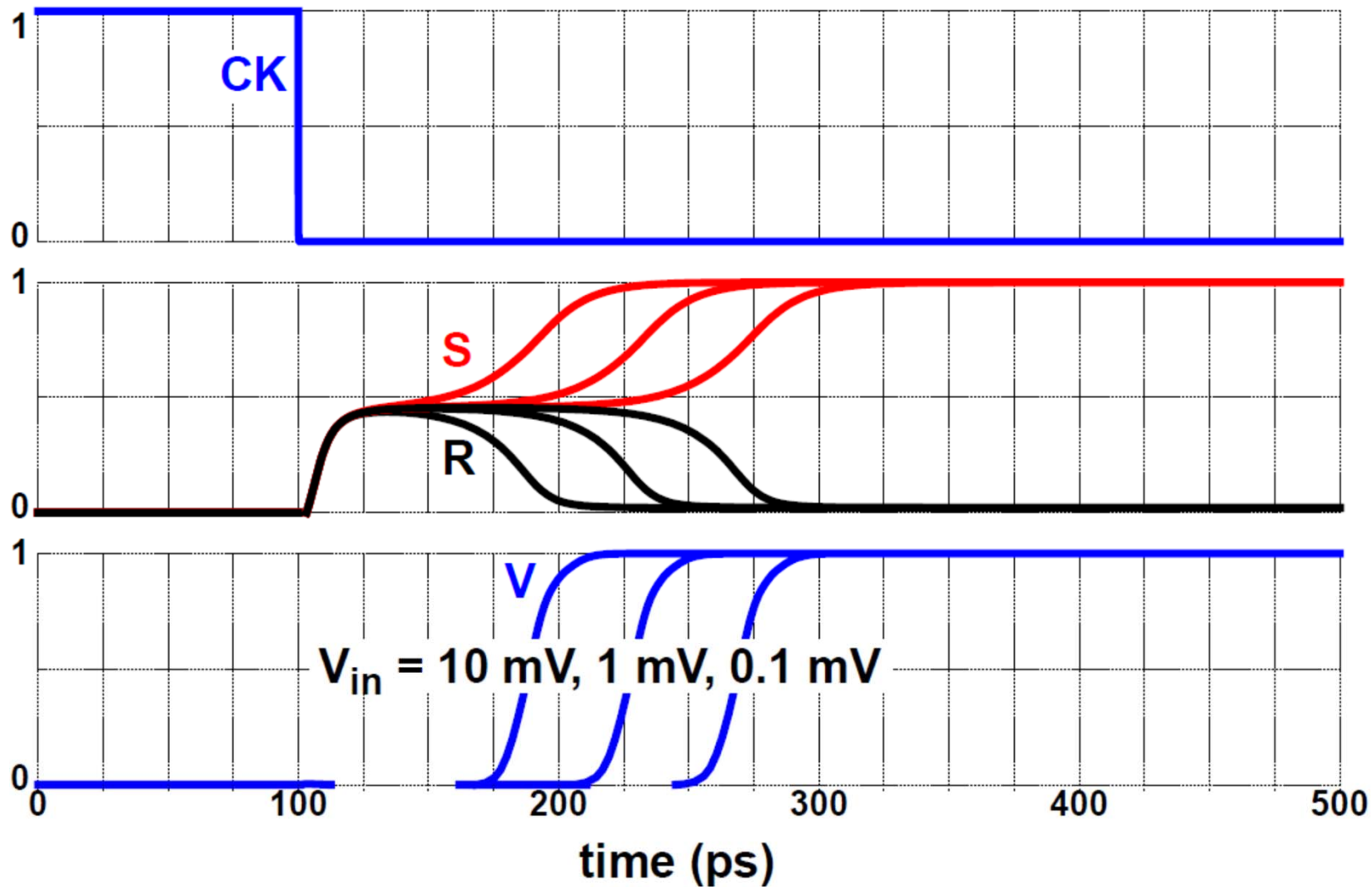
- Quick design in 65nm with  $V_{DD}=1V$



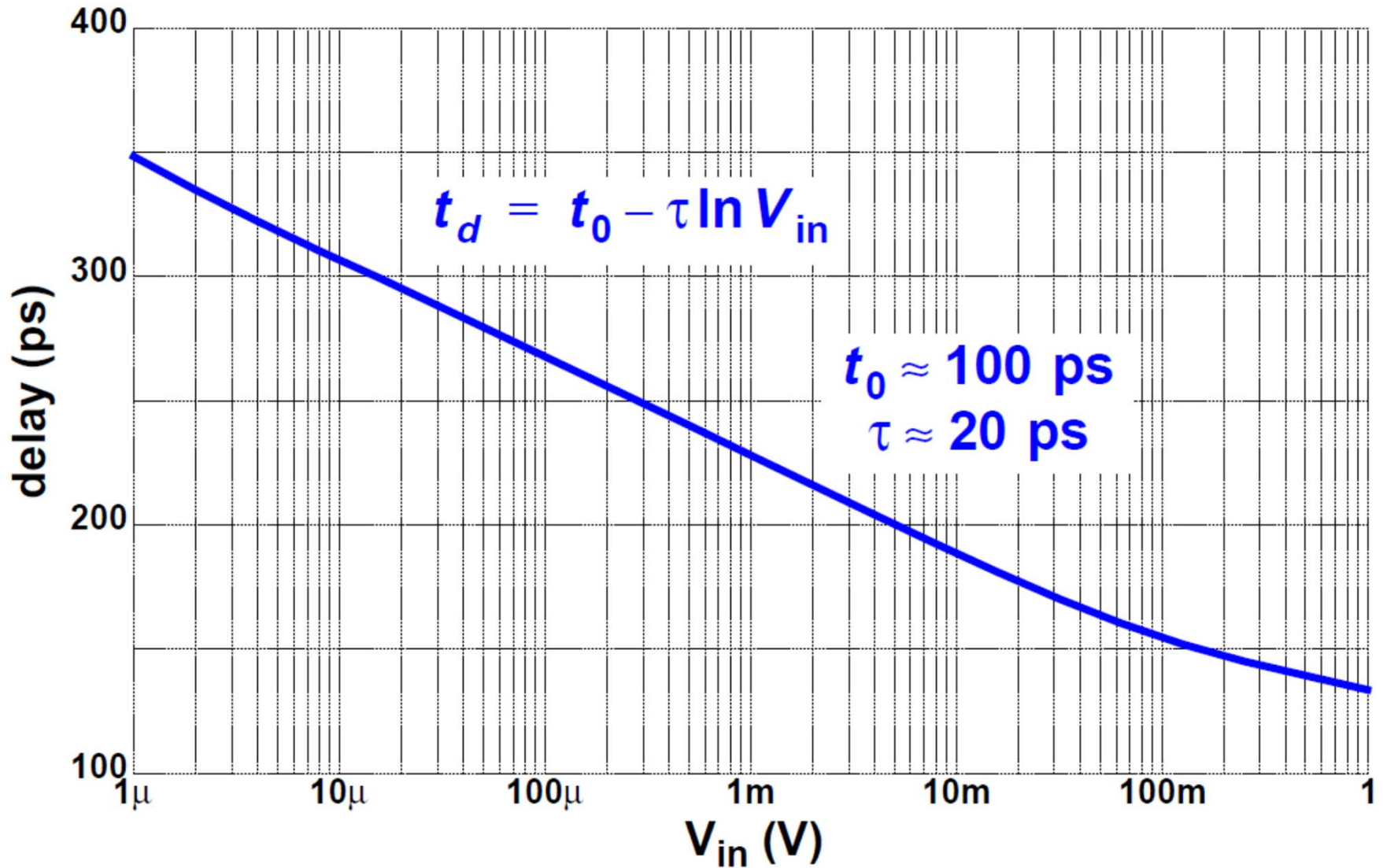
# Better Design



# Responses for Various $V_{in}$

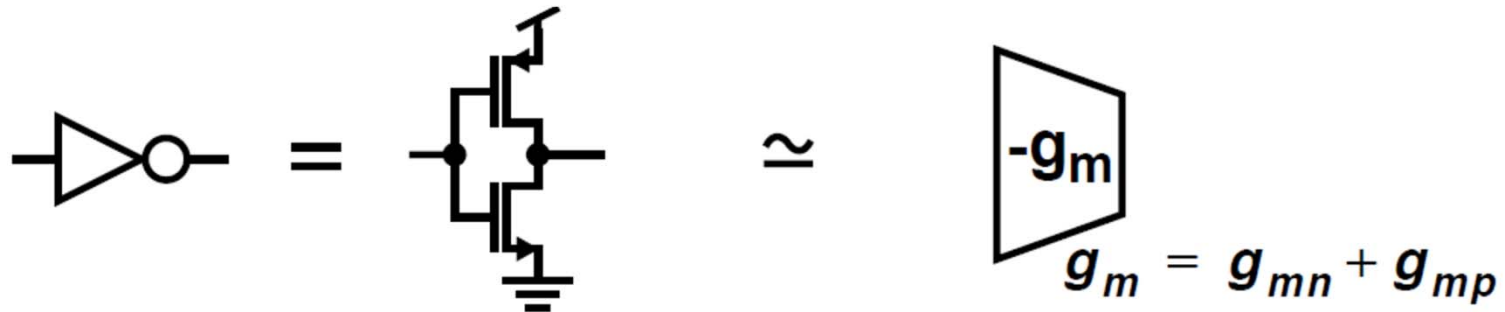


# Delay vs $V_{in}$

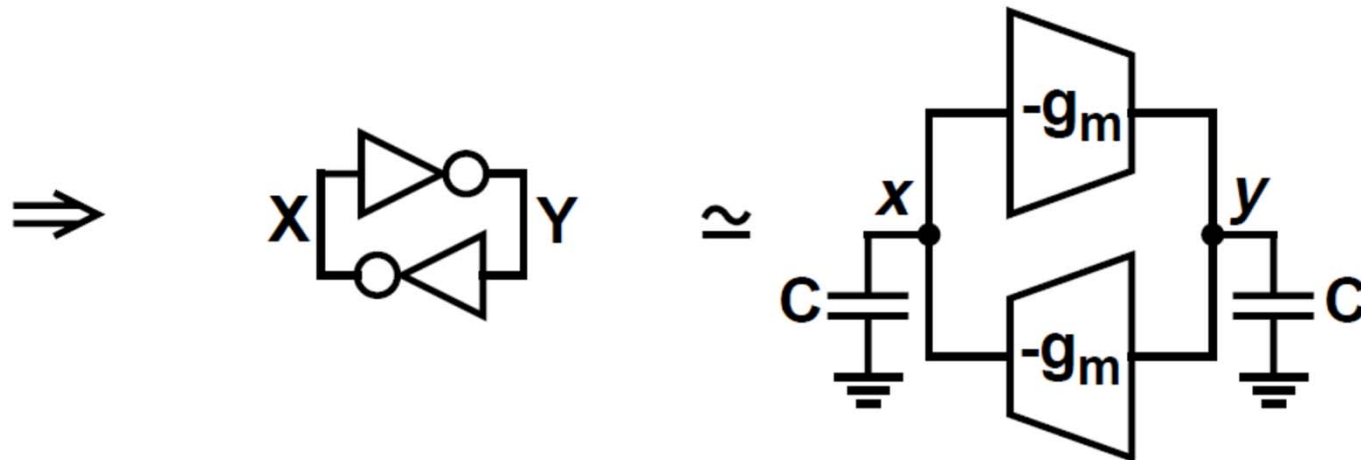


# Latch Mode Dynamics

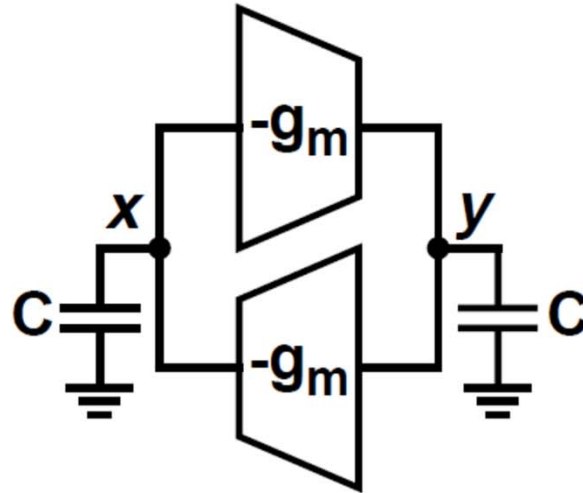
- For  $V_{in}$  near the trip point, an inverter is essentially just a transconductor:



- So near balance the comparator looks like this:



# Small-Signal Analysis



$$C\dot{x} = -g_m y$$

$$C\dot{y} = -g_m x$$

$$v_d = x - y$$

$$v_{cm} = \frac{x + y}{2}$$

$$C\dot{v}_d = g_m v_d$$

$$v_d(t) = v_{d0} e^{t/\tau}$$

$$C\dot{v}_{cm} = -g_m v_{cm}$$

$$v_{cm}(t) = v_{cm0} e^{-t/\tau}$$

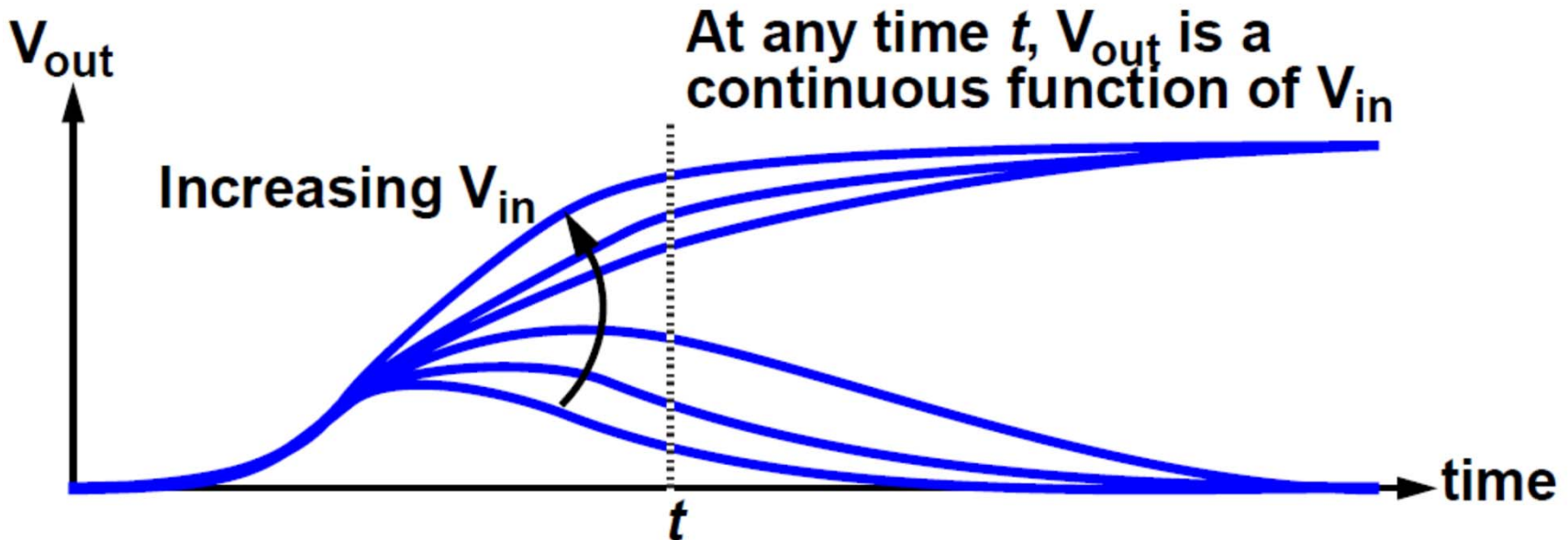
$$\tau = \frac{C}{g_m}$$

- Differential component grows exponentially
- CM component decays exponentially



# Metastability

- Metastability is fundamentally unavoidable
- Assuming the universe is continuous and deterministic, a comparator can be unresolved for any length of time



# Probability of Error

$$\begin{aligned} P_E &= P\{\text{not resolved by time } t\} \\ &= P\{V_{in} < e^{-(t-t_0)/\tau}\} \end{aligned}$$

- Take  $t_0 = 100\text{ps}$  and  $\tau = 20\text{ps}$
- Then for  $t = 500\text{ps}$  (1 GHz clock with a half-cycle between the comparator's clock and the clock of the subsequent latch),

$$P_E = P\{|V_{in}| < 2 \text{ nV}\}$$

- Assuming  $V_{in}$  is uniformly distributed in  $[-0.5, +0.5]$  V,  $P_E = 2 \times 10^{-9}$

Metastability occurs twice a second!

# Metastability Summary

- **Metastability is unavoidable**

All you can do is make  $\tau$  small and give enough time for regeneration to make  $P_E$  small

- **At best, metastability causes SNR degradation**

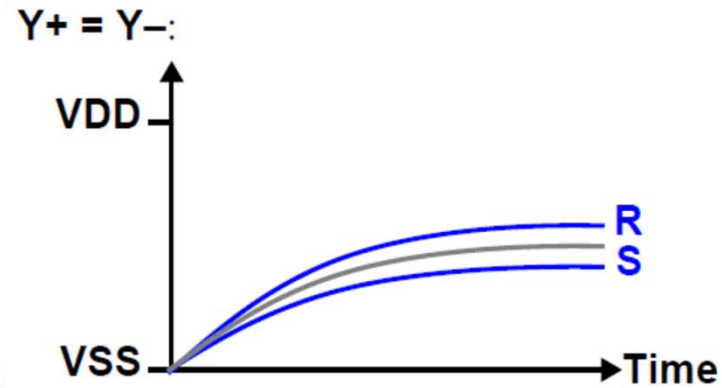
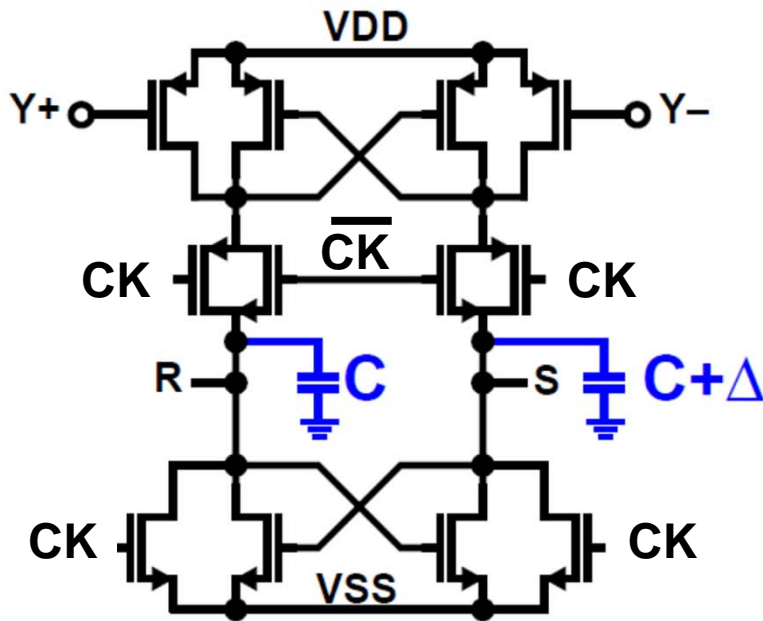
At worst, it causes a system failure

- **In Continuous-Time  $\Delta\Sigma$  Lecture we will look at metastability further**

Find SNR equation for a CT  $\Delta\Sigma$  ADC



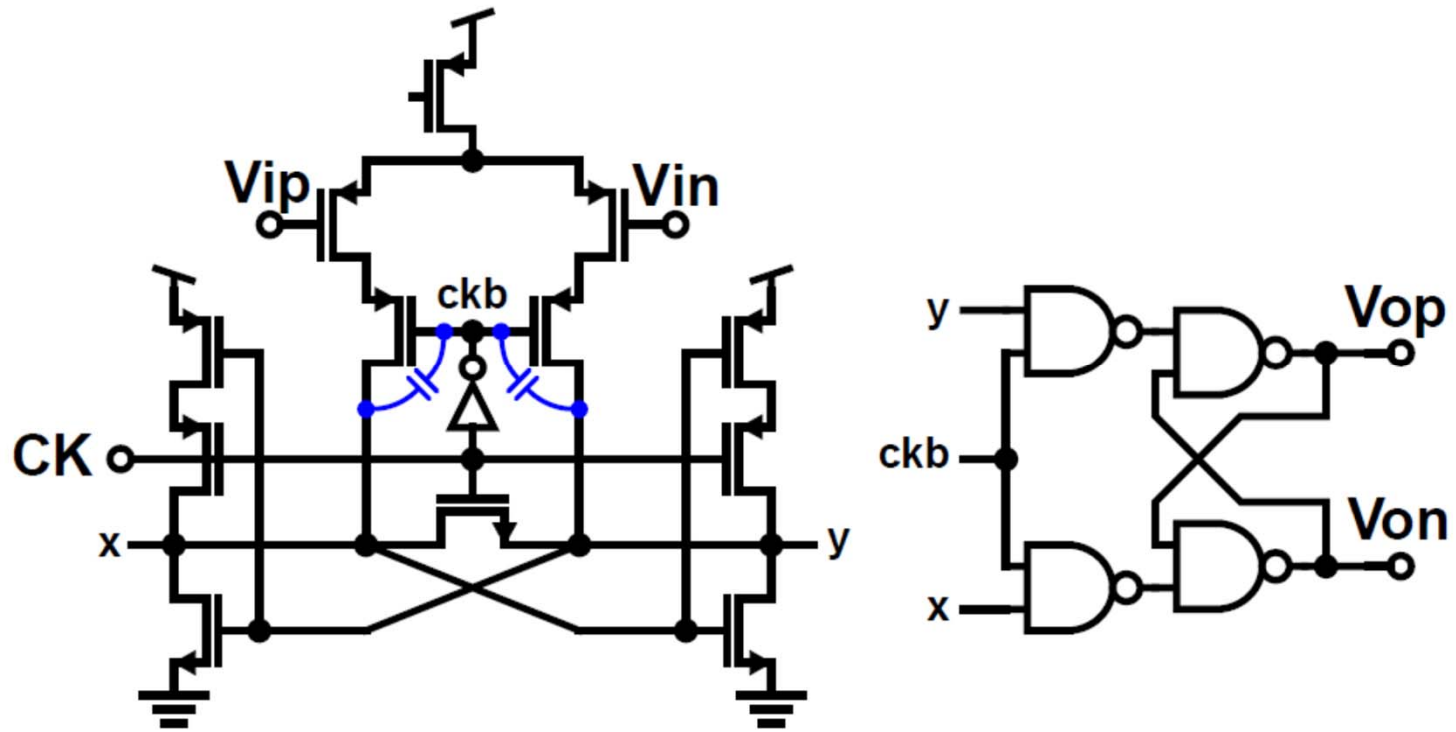
# Dynamic Offset



**S rises more slowly than R  
⇒ offset**

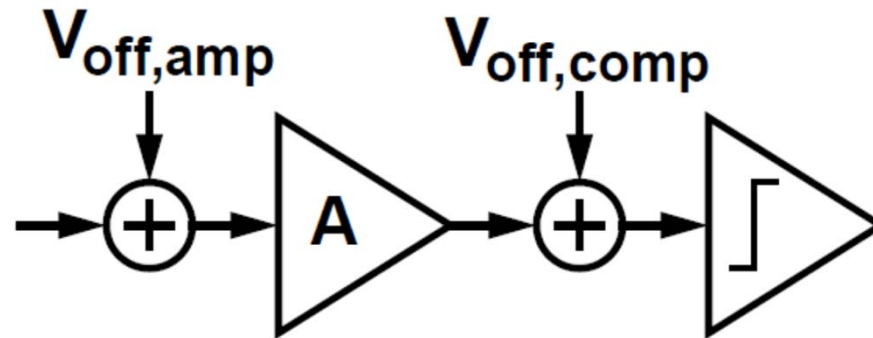
- **Mismatched parasitic capacitance causes offset**  
20 mV/fF for this comparator
- **We can fix this with better design**

# Improved Comparator



- **Reset when  $CK = 1$ , regenerates when  $CK = 0$**
- **$x$  &  $y$  don't step if biased properly**  
Mismatch in overlap capacitance still a problem

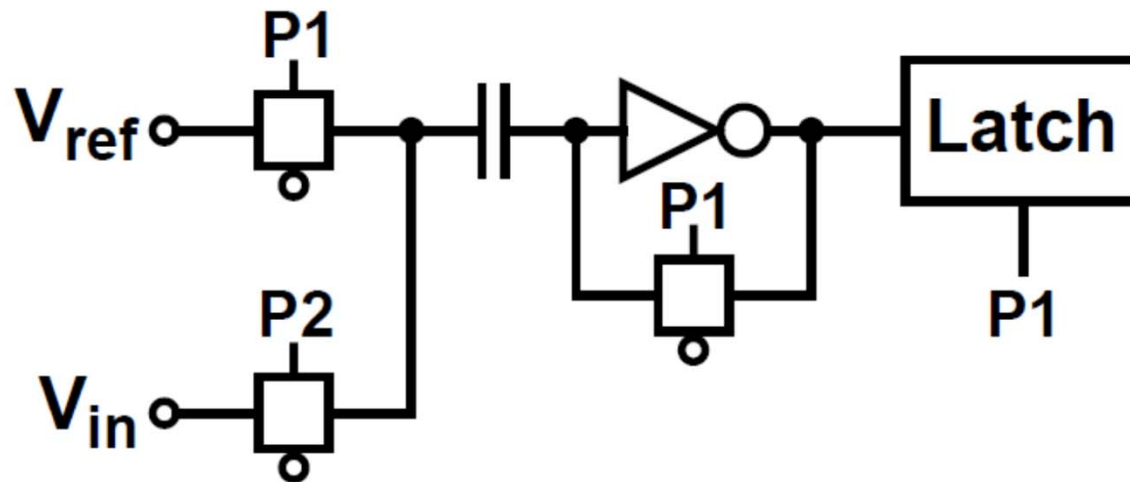
# Reducing Offset with a Preamp



$$V_{\text{off,tot}} = V_{\text{off,amp}} + V_{\text{off,comp}} / A$$

- 😊 **Comparator offset is reduced by preamp gain**  
Amplifier offset dominates
- 😊 **Amplifier also isolates driving stage from 'charge kickback'**
- 😞 **Amplifier bandwidth limits speed**

# Auto-Zeroed SC Comparator



- During P1, the inverter/amplifier is biased at its threshold/offset voltage
- During P2, the difference between  $V_{in}$  and  $V_{ref}$  is amplified

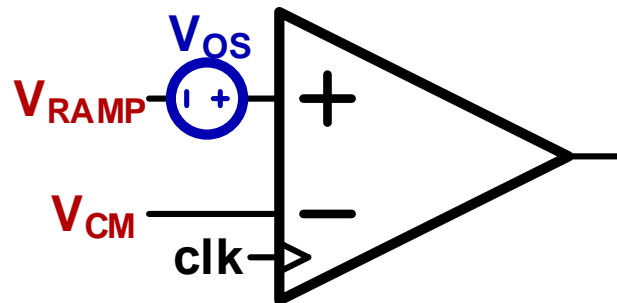


# Measuring Offset

- In ideal schematic, differential comparator has no offset

Monte Carlo simulations will show offsets in comparator due to mismatch

Additional offsets will be seen in extracted layout (should be small with good layout)



- Traditional measurement

In a given MC trial, ramp the input across the threshold of the comparator, crossing point is the offset

Requires ~50-100 transient trials, each one ~10 cycles

# Measuring Offset

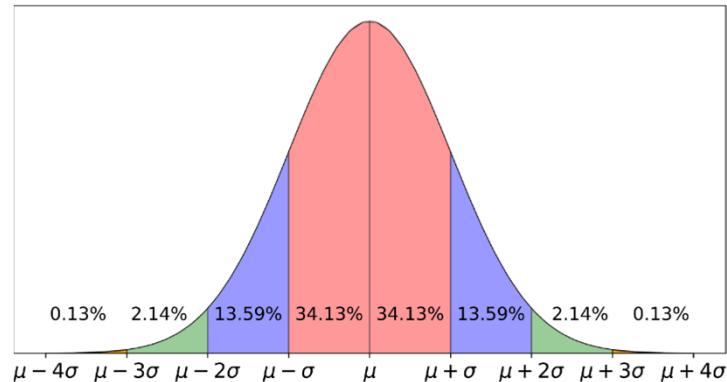
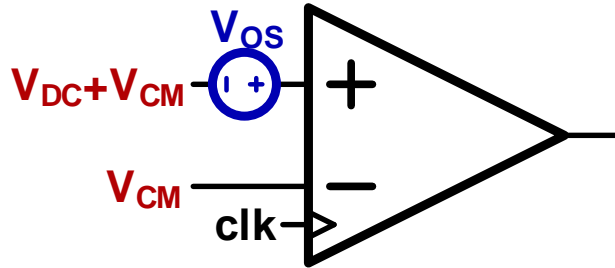
- **Alternative Method**

In a single Monte Carlo trial, set a DC input voltage and run the transient for a single cycle

Repeat ~100 transient single cycle MC trials

Determine percentage of sims that output +1 or -1

Assuming normal distribution, offset can be determined



- **Example: DC voltage = 1mV**

**84%** output '+1', 16% output '-1' → Offset is 1mV

Wolfram Alpha: -inverse erfc(2\***0.84**)\*sqrt(2)

# Measuring Noise

- Output is latched, a traditional AC noise sim is insufficient
- Simulate using Offset measurement technique

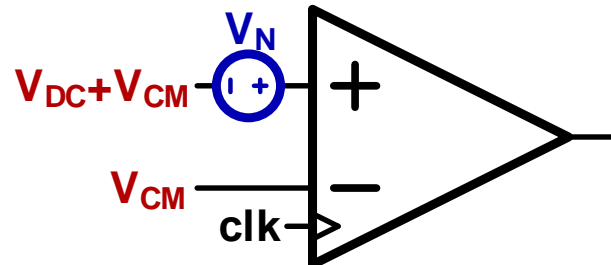
In a given transient noise simulation, set a DC input voltage and run the transient for a single cycle

Repeat ~100 transient noise single-cycle simulations

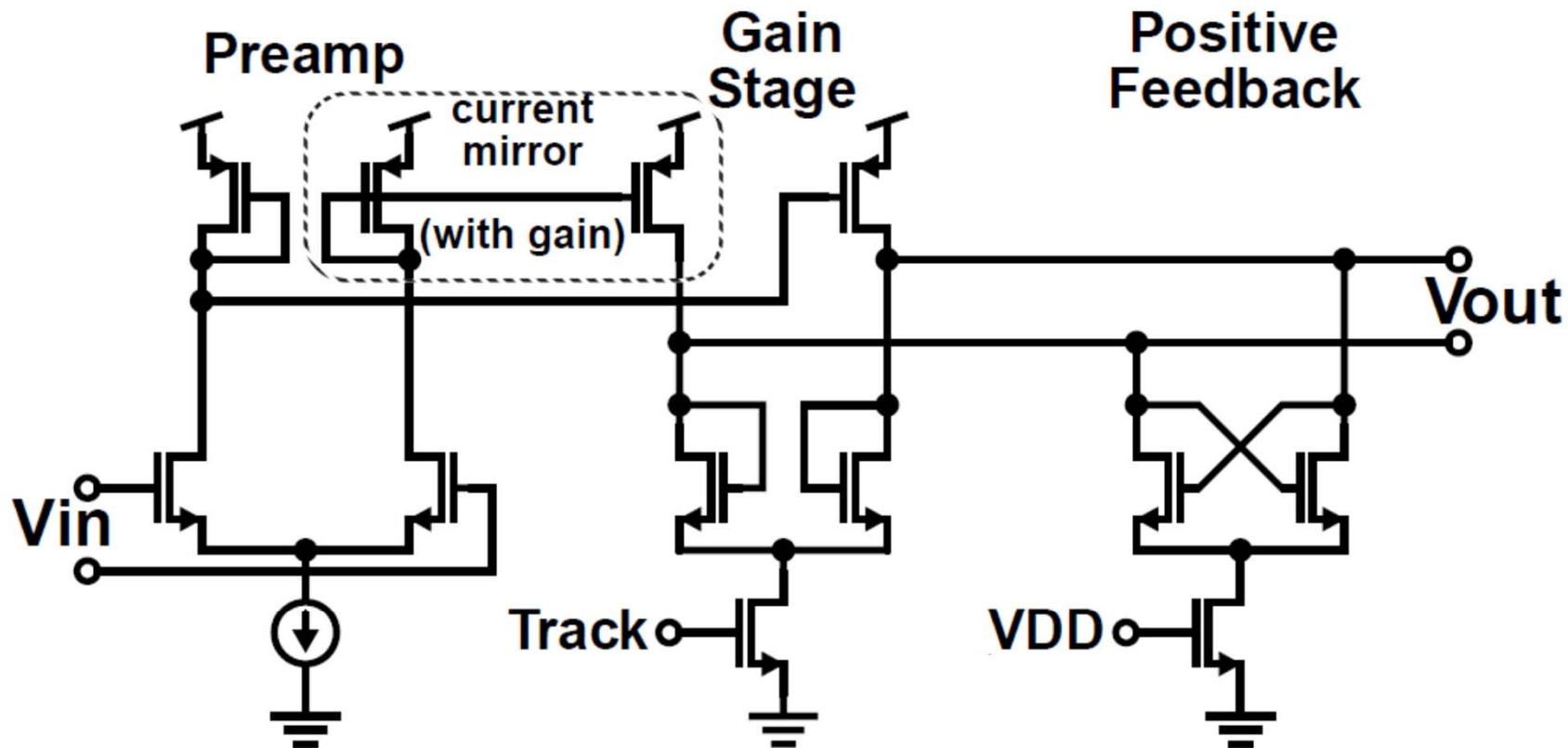
Determine percentage of sims that output +1 or -1

Assuming normal distribution, offset can be determined

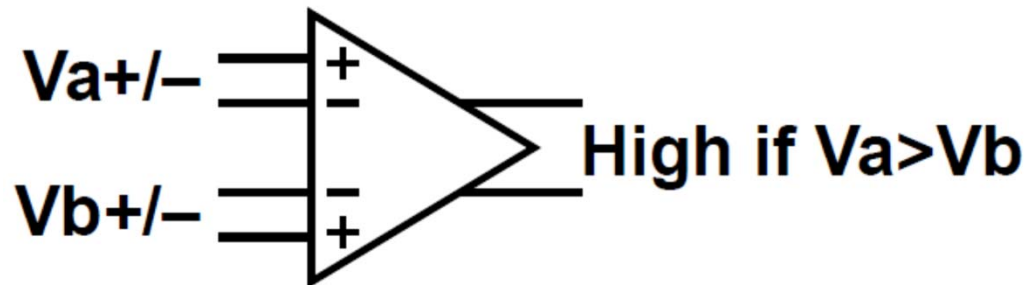
[Razavi 2015]



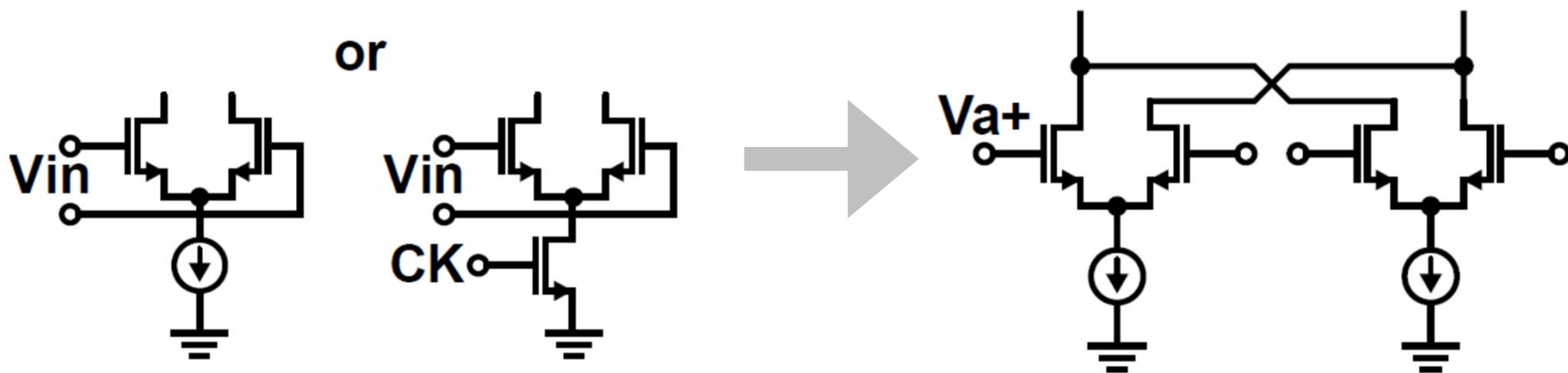
# Comparator with Preamp



# Dual-Difference Comparator

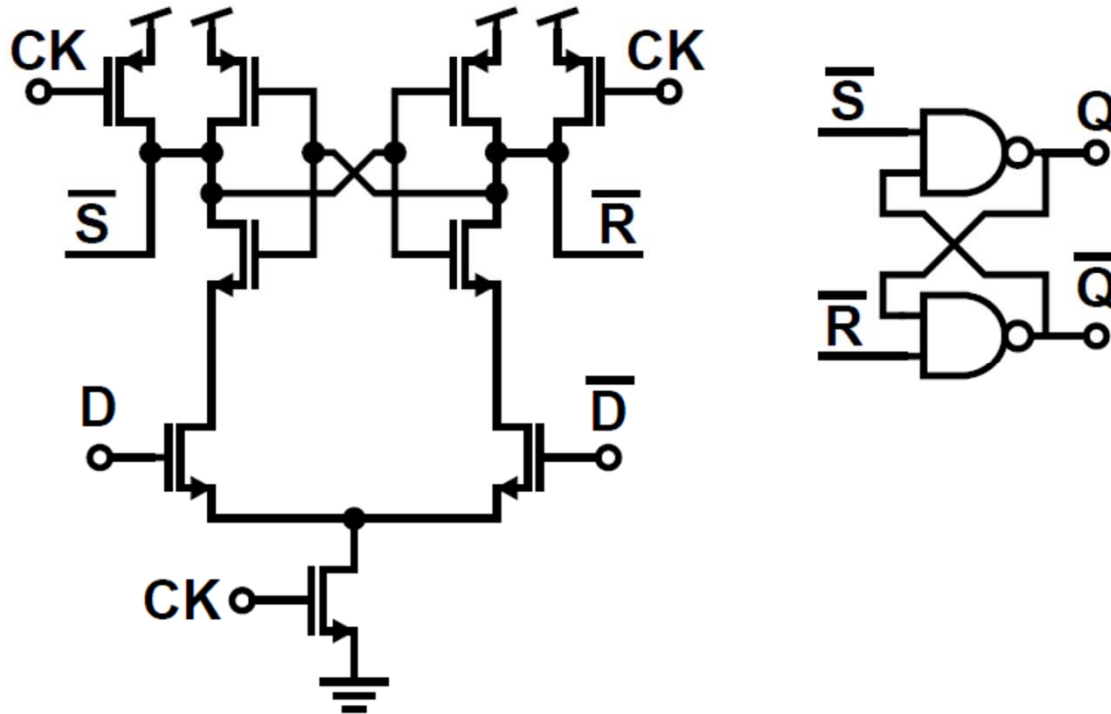


- In any of our comparator circuits, make the following replacement



- Where should  $V_{a-}$  go?

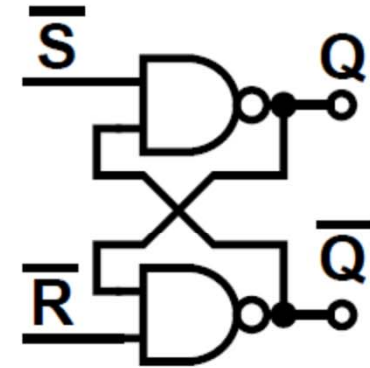
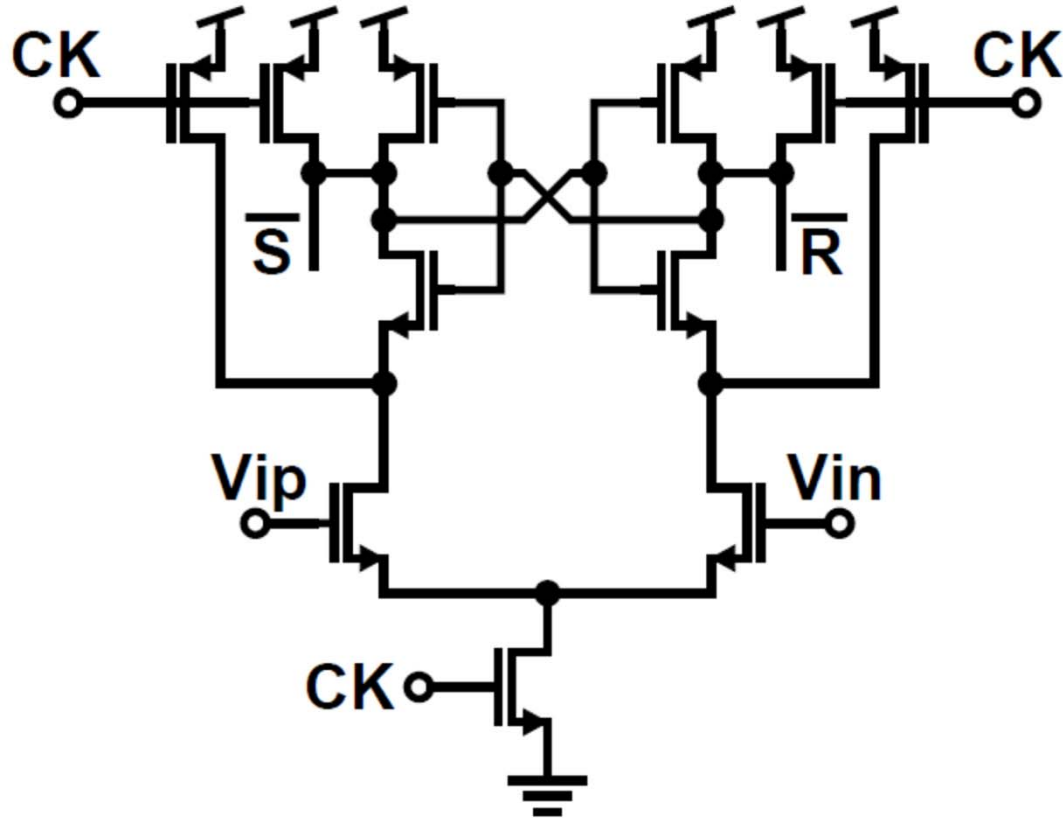
# StrongArm Latch



- No static current
- Can be used as a comparator

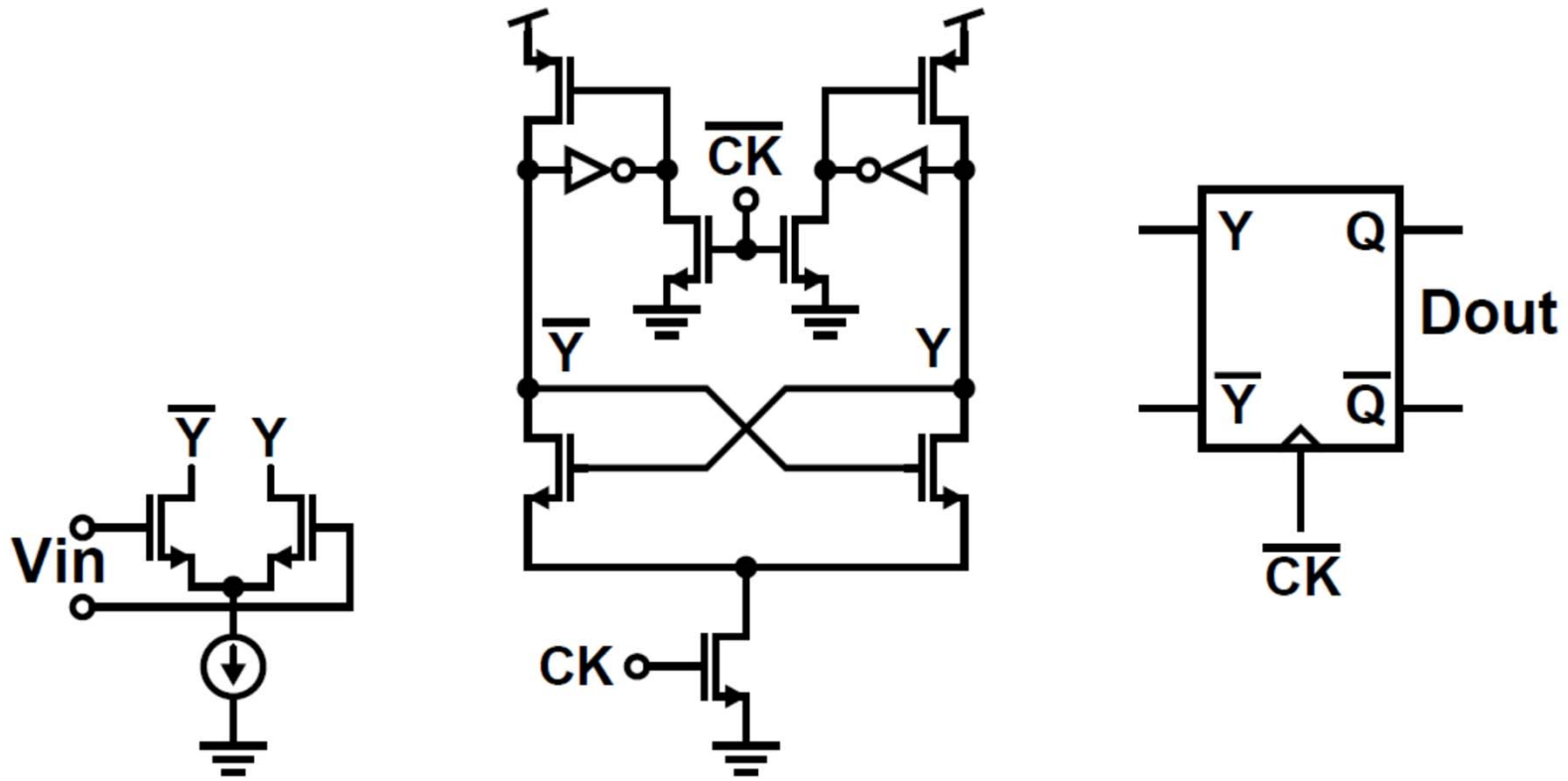
Note that input CM voltage defines the bias point during regeneration

# StrongArm Latch



- **Well-defined initial state  $\rightarrow$  less hysteresis**  
[2014 Abidi] 'Understanding the Regenerative...'  
[2015 Razavi], 'The StrongARM Latch'

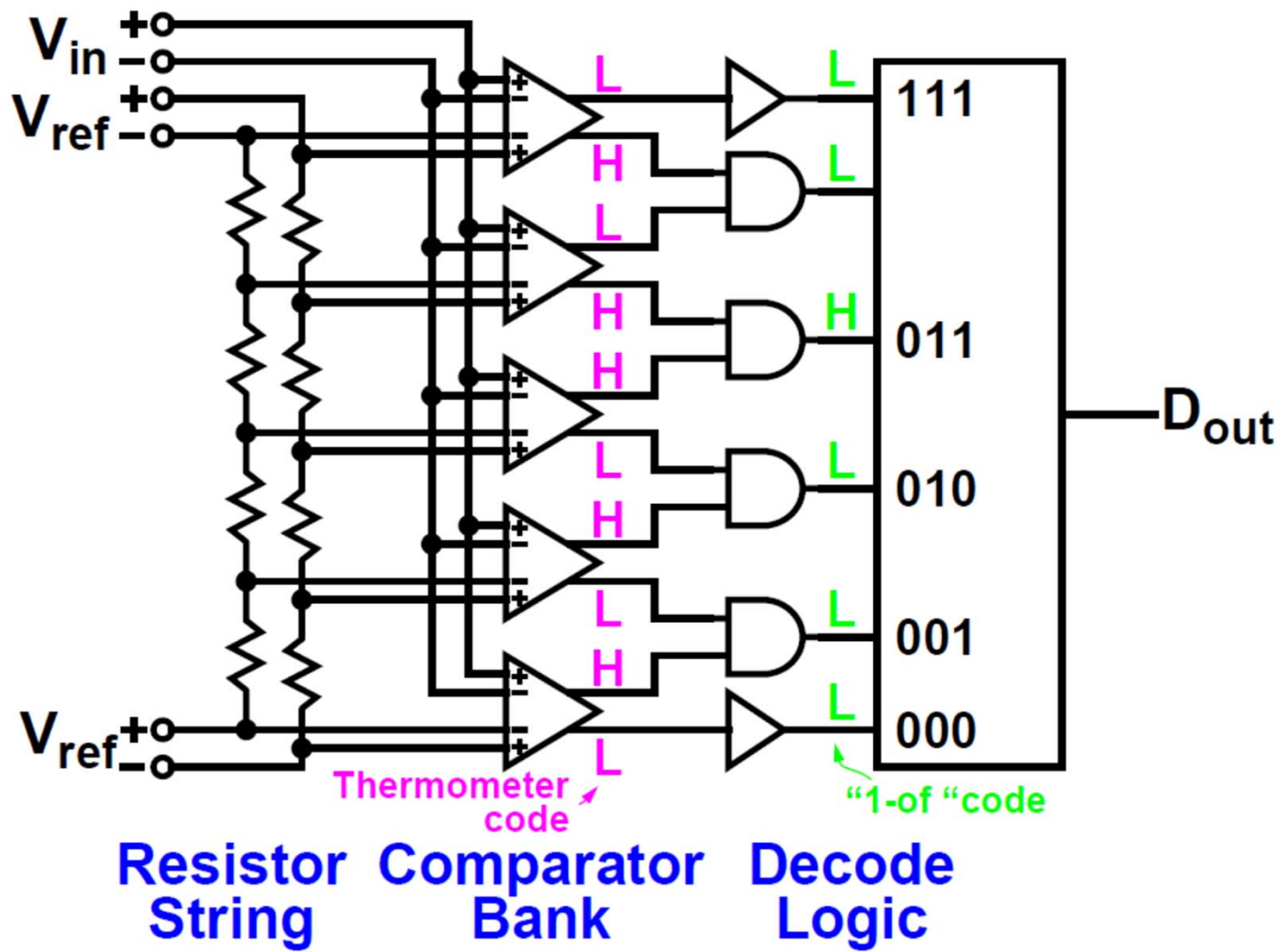
# Yang's High-Speed Comparator



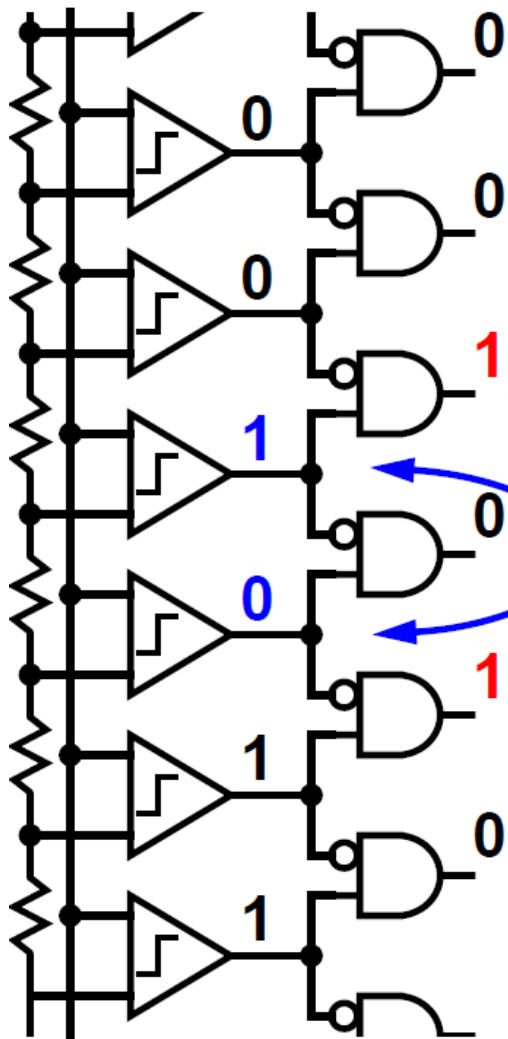
- $\tau_{nom} = 6ps$  in 65nm CMOS  
Used in a CT $\Delta\Sigma$  ADC clocked at 4 GHz [Shibata2012]



# Flash ADC



# Flash Bubbles

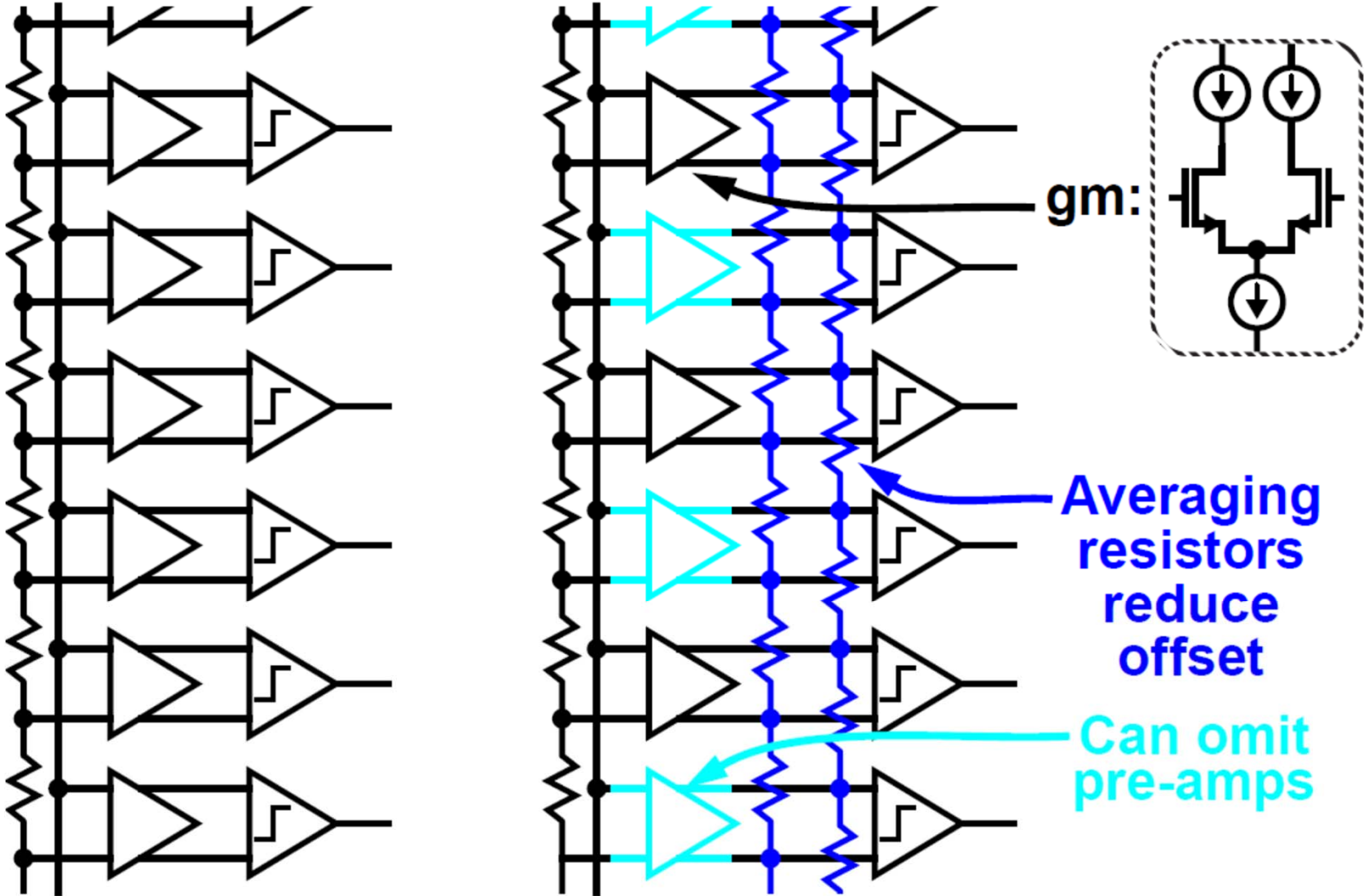


- Need to modify logic to handle bubbles gracefully unless bubbles guaranteed to not occur

- Counting the number of 1s is the safest method

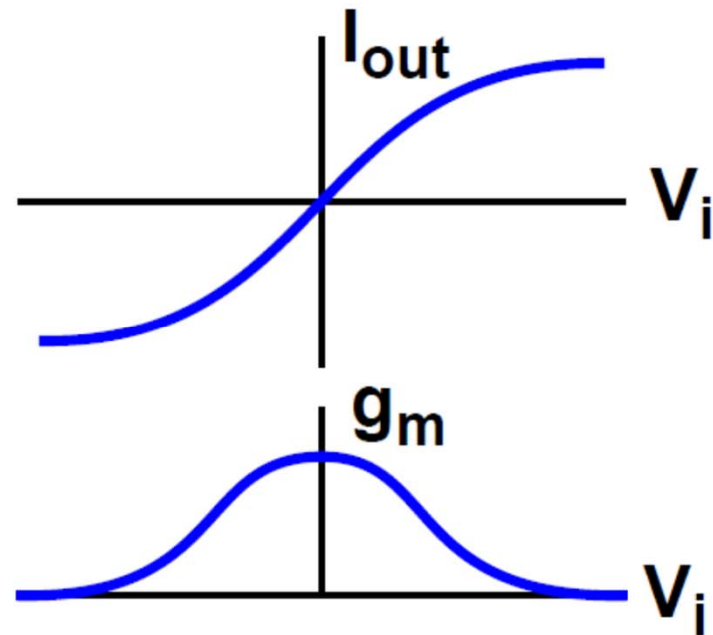
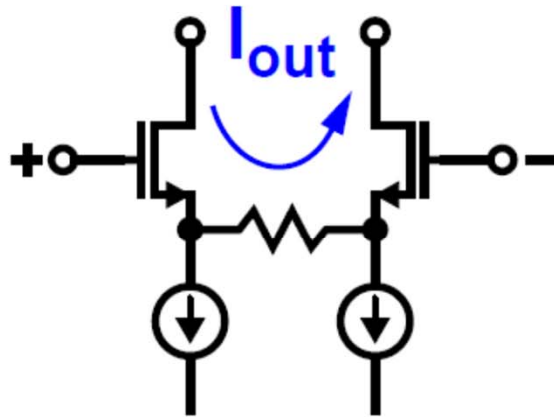
Use a 'Wallace-Tree Adder'

# Averaging and Interpolation



# Circuit of the Day: Linear Transconductors

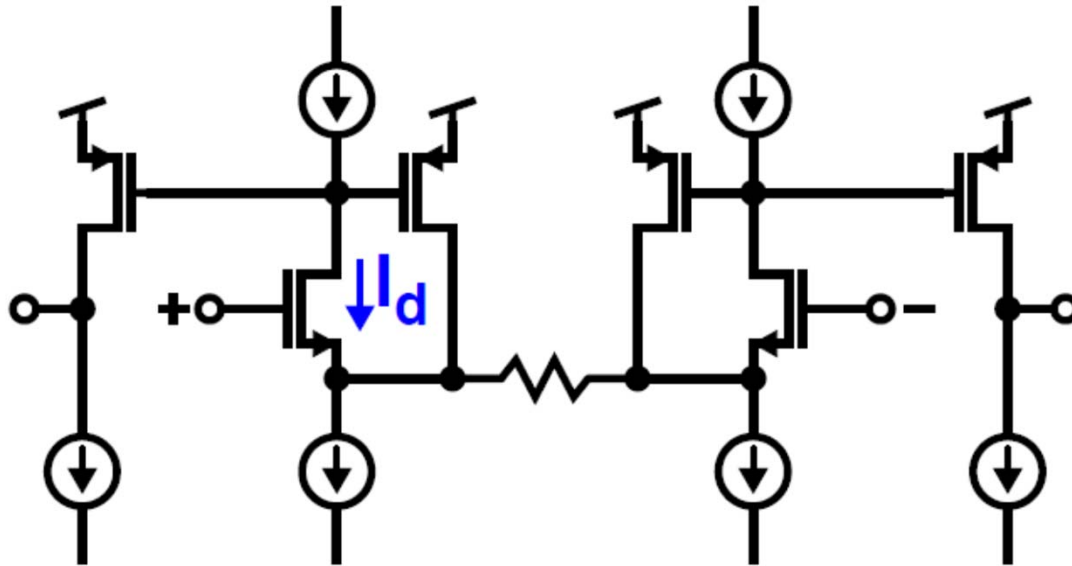
- Degenerated Differential Pair



- $V_{gs}$  varies nonlinearly with  $I_{out}$   
 $g_m$  is nonlinear  
Increase  $I_{bias}$  to improve linearity

# Linear Transconductors

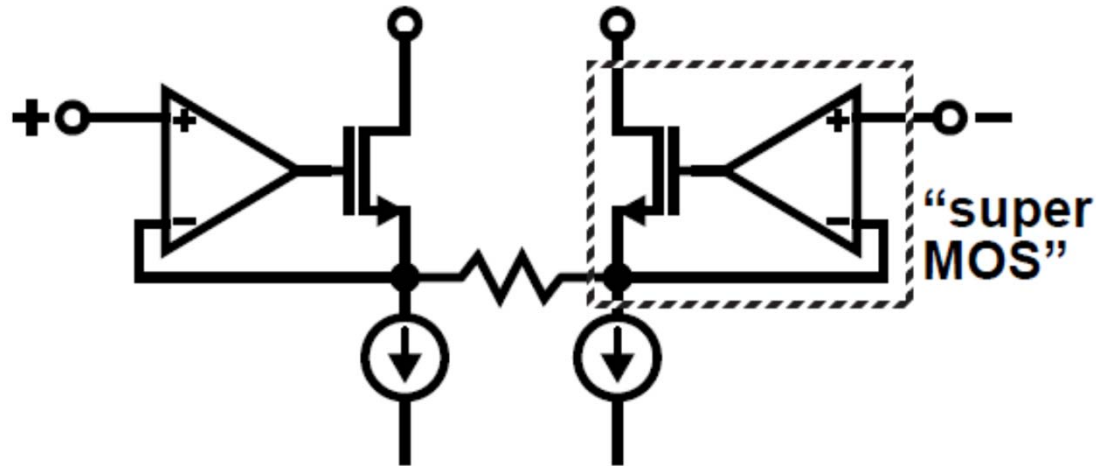
- Force Constant  $V_{gs}$



- $I_d$  constant  $\rightarrow V_{gs}$  constant
- Linearity dependent on current-mirror linearity

# Linear Transconductors

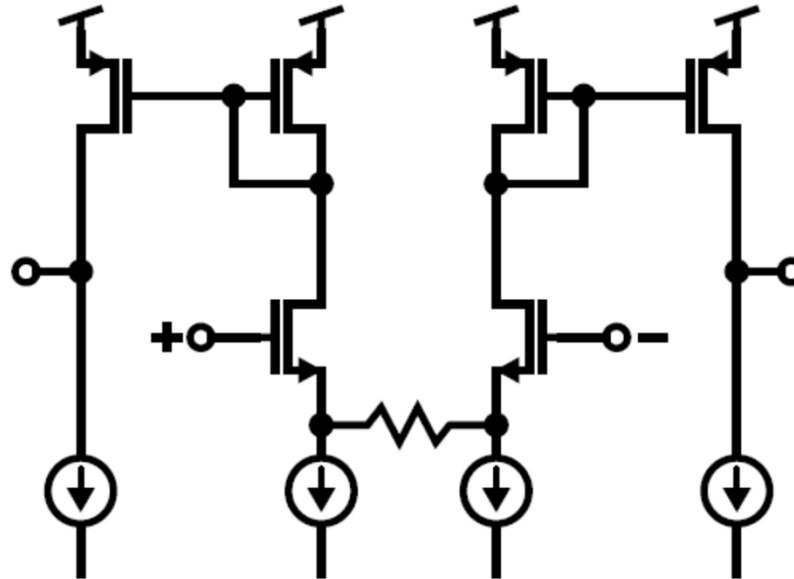
- Add Op Amps



- Linearity limited only by op amp gain and BW
- High output resistance
- Output compliance depends on input swing

# Linear Transconductors

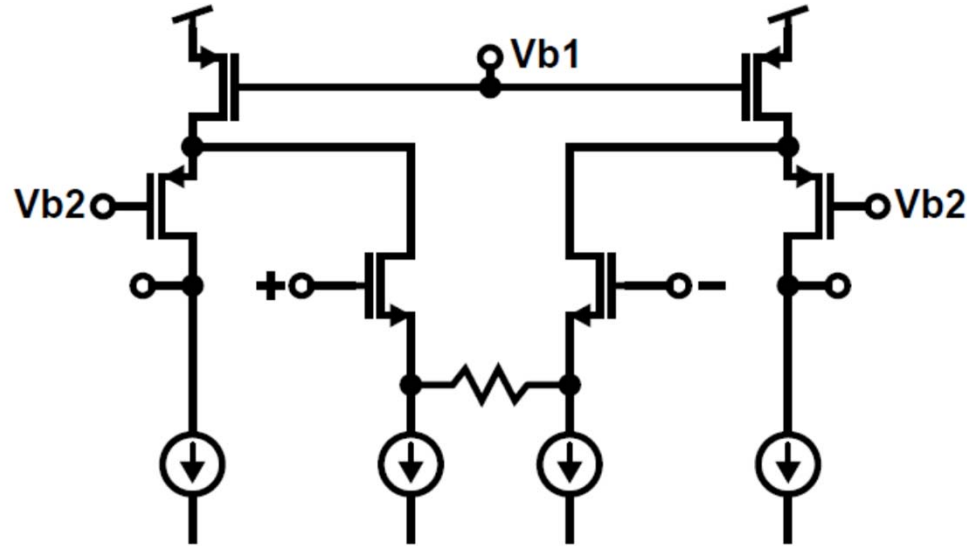
- Mirror the Output Current



- 😊 Output compliance is  $V_{DD} - 2V_{dsat}$
- ☹️ Top of differential pair at  $V_{DD} - V_{gs}$

# Linear Transconductance

- Fold the Output Current



- 😊 Increased headroom for differential pair
- 😊 Increased output resistance
- 😞 Extra cascode in output branch



# Homework #3 (Due Feb 11)

- **Read ‘The StrongARM Latch’ [Razavi 2015]**
  - 1. Design a version of this comparator including the subsequent RS latch**
    - A. Make sure your schematic is complete and legible**
  - 2. State the power consumption at  $F_{ck} = 100$  MHz, regeneration time constant ( $\tau$ ),  $t_0$ , rms noise and the mean and standard deviation of the offset**
    - A. Use nominal PTV**
    - B. Summarize the specifications in a table**
    - C. Include both hand calculations and simulation results**

# What You Learned Today

- **Example Comparator Circuit**
- **Comparator metrics**
  - Metastability and regeneration time constant
  - Offset measurement
  - Noise measurement
- **Flash ADC**